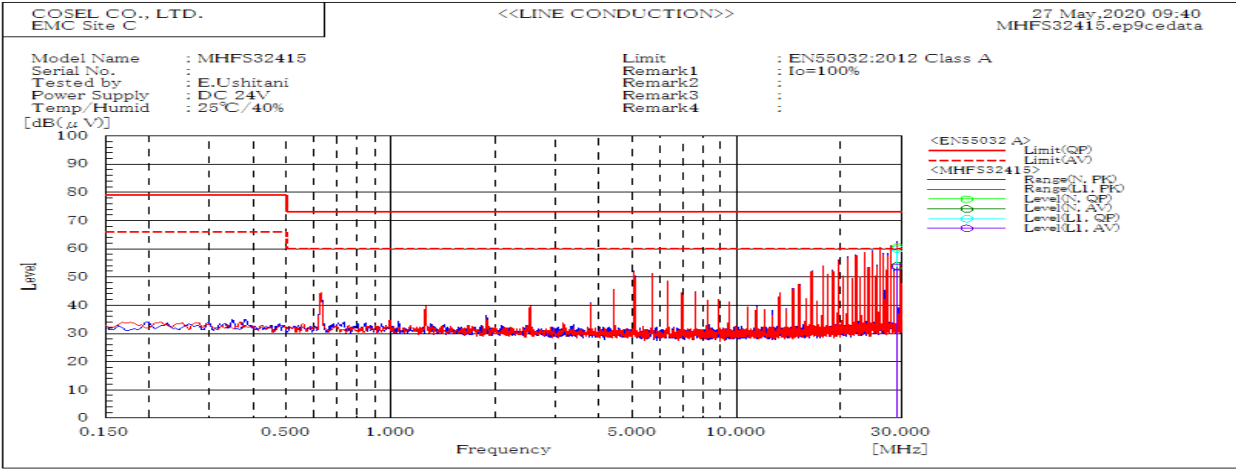
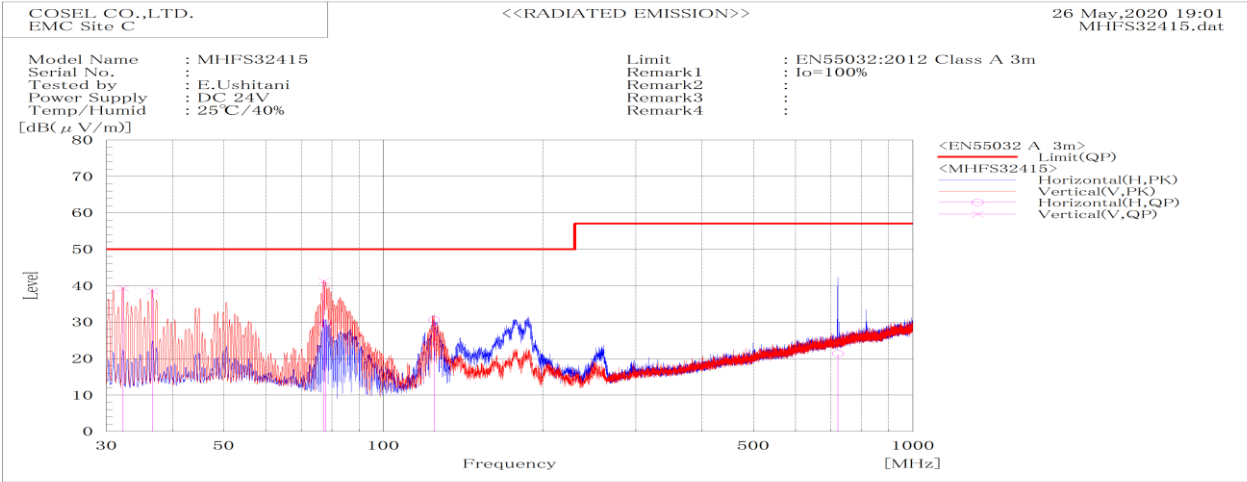


DATA SHEET		Date	04-Jun-20
Model	MHFS32415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



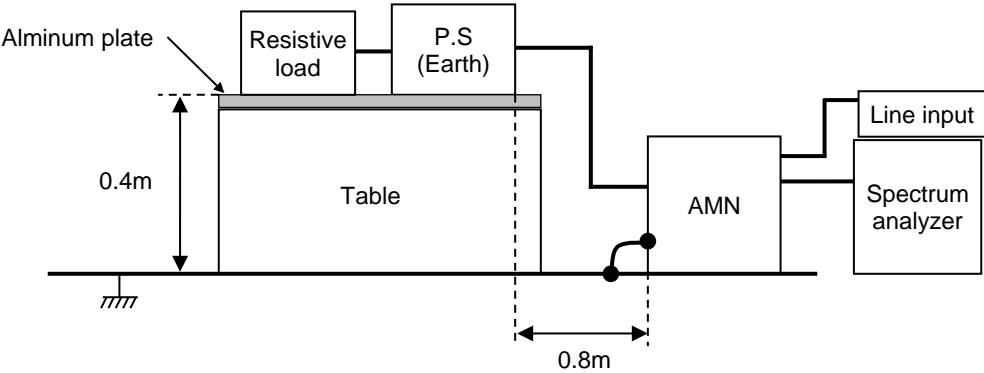
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
29.082	L1	60	53.5	73	60	13	6.5	Pass	
29.067	N	60.6	54	73	60	12.4	6	Pass	



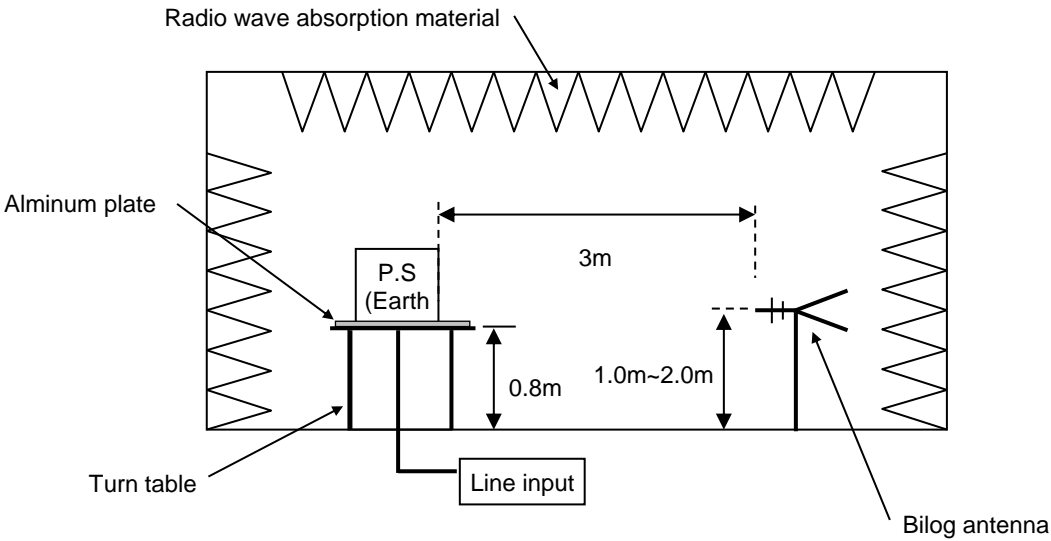
Frequency MHz	Polarization	Stability	Level		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
77.795	H	Stable	29.7	50	20.3	Pass	100	140.6		
124.65	H	Stable	30.6	50	19.4	Pass	199.7	332.5		
722.041	H	Stable	21.3	57	35.7	Pass	196	1.5		
77.158	V	Stable	41.2	50	8.8	Pass	103.6	246.9		
32.251	V	Stable	39.3	50	10.7	Pass	100	101.2		
36.682	V	Stable	38.5	50	11.5	Pass	100.2	182.5		

DATA SHEET		Date	04-Jun-20
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission



Conditions

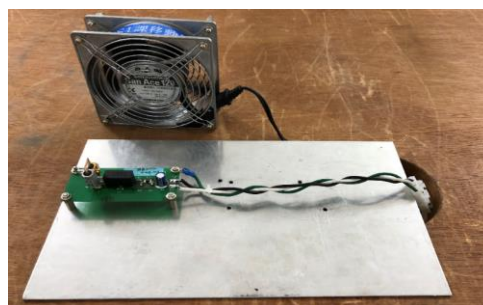
Test : EMI
Model Name: MHFS3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

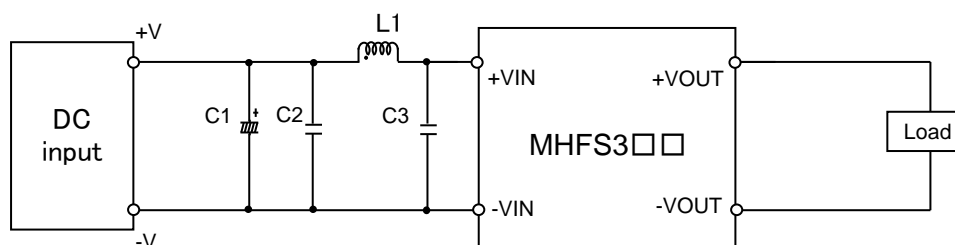


Fig.1 Testing circuitry

C1 :	MHFS312□□	50V 100μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS324□□	-
	MHFS348□□	-
C2 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS312□□	1200mA 4.7μ H Inductor(LQH32PN4R7NNCL MURATA MANUFACTURING)
	MHFS324□□	900mA 10μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
	MHFS348□□	550mA 22μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)